

BiTS 2001 in the News

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BiTS WorkShop

By Bill Mann (IEEE)

The second annual Burn In and Test Socket Workshop was held in Mesa Arizona from March 4 - 7, 2001. The Test Technology Technical Council of the IEEE Computer Society sponsors this workshop and about thirty others on specialized testing topics. The General Chair, Fred Taber from IBM Microelectronics, said that the attendance of 250, was up 25% from last year. In a period of limited discretionary travel budgets, Fred noted, "BiTS clearly serves an industry need. His committee put together an excellent Technical Program. It began with a panel discussion and lively audience participation on the topic of Broad Package Specifications: And the Socket Is Expected To Always Work?

The Keynote Speaker was Dr. Tom Di Stefano, President of Decision Track. Dr. Di Stefano spoke on "Wafer Level Paradigm For Burn-in And Test," and he observed that "wafer level packaging promises to reshape our world of packaging and test." There were twenty-four presentations in eight sessions covering the areas of contacts, sockets, burn-in boards, thermal modeling and analysis, new products, full wafer level contact methods and industry trends. The Best Data award went to Nancy Dean of Honeywell Electronic Materials for *Low Cost Thermal Management Using Compliant Thermal Interface Materials*. The Most Inspirational award was for *Embedded Test Solution For Burn-in* by Charles McDonald of LogicVision (presented by Steve Pateras of LogicVision). The Best Presentation was by Mark Miller of AMD for *Next Generation Burn-in & Test System For The Athlon Microprocessor: "Hybrid Burn-in."*

For the first time, the technical pro-gram was complemented with small vendor displays. Twenty-four suppliers showed their products and/or services during breaks in the program. Copies of the presentations can be obtained at: www.bitsworkshop.org

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